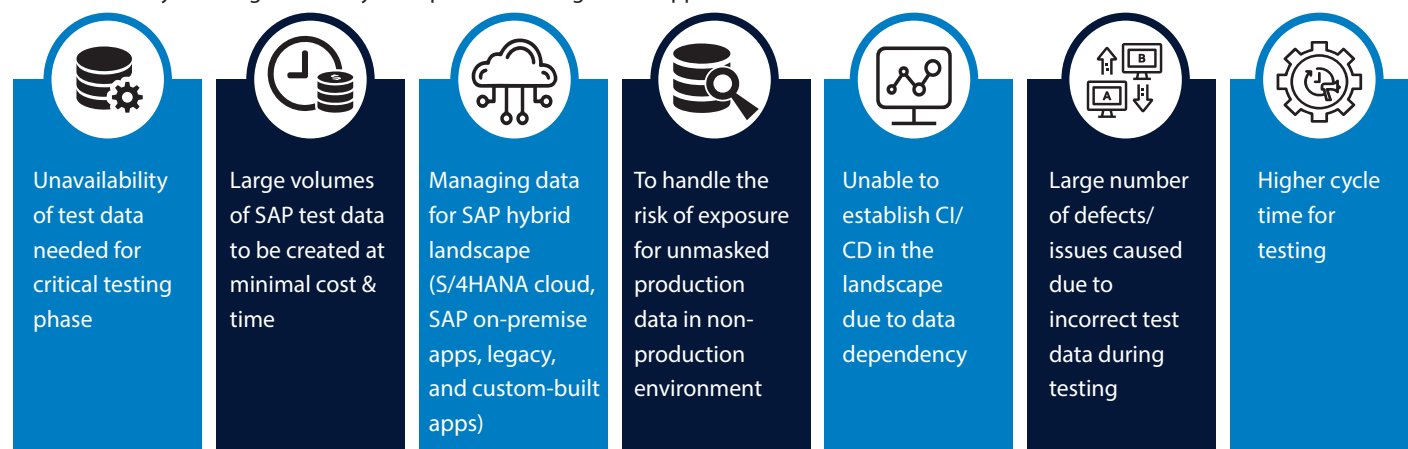


INFOSYS–BROADCOM INTEGRATED TEST DATA MANAGEMENT SOLUTION FOR SAP

Enables Test Data Management efficiently across Hybrid (on-premise / cloud) SAP ecosystems

Organizations across the globe are making a transition to agile ways of working in this dynamic market to stay relevant. Additionally, technology advancements like cloud are transforming the organizations entire IT landscape. These changes have brought about a change in test data needs of the organizations. The need of the hour is to provide the right test data, in the right quantity, and at the right time, in a non-production environment.

Some of the key challenges faced by enterprises in testing of SAP applications are:



To address the above, Infosys with its strong SAP and TDM expertise along with Broadcom jointly developed an end-to-end testing solution across SAP known as **Infosys–Broadcom Integrated Test Data Management Solution for SAP**. This solution supports enterprises in providing accelerated next-gen Test Data Management (TDM) services for intelligent masking, data generation, data sub-setting (based on time window and process variants), data copy (master and transactional data), self-service TDM, and test data integration with CI/CD pipelines.

Infosys – Broadcom Integrated Test Data Management Solution for SAP:

The solution extracts data from production environment into staging (known as gold copy). Data is then consistently masked in gold copy. Masked data gets loaded on to the test environment either on cloud or on-premise in the desired quantity (with sub-setting).

The in-built data mining feature helps retrieve right test data sets from the test environment based on test criteria. Additionally, synthetic data can be generated into the test environment based on test requirements. Data in test environments will be periodically refreshed to ensure availability of quality test data.

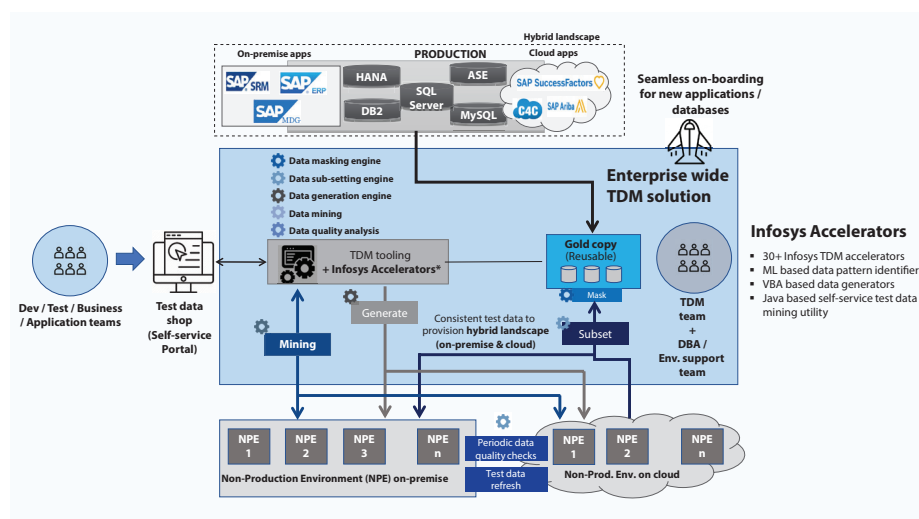


Fig1: Infosys – Broadcom Integrated Test Data Management (TDM) Solution for SAP

Key solution features:

Intelligent masking:

- Identifies sensitive fields in SAP using ML algorithms
- Automatically identifies logical relationship between SAP tables and fields selected for masking

TDM process automation:

- Performs workflow-based test data provisioning processes for data extraction, data sub-setting, data masking, data loading and data generation
- Automates data preparation activity for SAP master and transaction data using open source tools (Selenium, Java and Python) or commercial testing tools
- Leverages RPA based techniques for TDM process automation

CI/CD and DevOps integration:

- Provisions SAP test data triggered from Jenkins tool for automated execution in a pipeline
- Enables zero-touch platform by invoking SAP data provisioning at runtime

Support hybrid SAP ecosystem:

- Supports wide variety of databases (Oracle, HANA, Sybase ASE, etc.) and applications (S/4HANA, CRM, ECC, Ariba, Concur, etc.)
- Supports data generation, data sub-setting, data masking and data mining for SAP systems (on-premise, cloud and multi-DB architecture) including data provisioning needs on Azure, AWS and GCP platforms

Agile support/self-service:

- Enables teams to be autonomous by giving them the ability to execute data set-up workflows themselves on TDM portal
- Supports on-demand SAP test data provisioning for agile teams
- Leverages chatbot for data selection from multiple SAP tables

Compliance and regulations:

- Ensures adherence to data privacy and compliance needs
- Supports dynamic masking techniques specific to SAP role-based data access
- Capable of masking PII (Personally identifiable information) data from SAP tables in compliance with GDPR regulations
- Performs periodic data quality checks to identify data anomalies and performs data refreshes to clean up inconsistent data

Benefits:

Delivery excellence

- Increased adoption of Test Data Management (TDM) self-service portal, thereby providing individual teams the ability to generate test data independently
- Minimized the impact on Business As Usual (BAU) during data extraction process
- Customized TDM process for data modelling, extraction, masking and data provisioning services
- Reduced cycle time by 90% for test data availability

TCO reduction

- Saved 60% of storage space using strong sub-setting principles
- Reduced test data cost by 25% with automation & reuse

Productivity improvement

- Reduced data identification effort by 30%
- Increased productivity by 30% with TDM governance
- Saved 40% effort in test data masking
- Reduced data refresh efforts by 45%

A success story

A leading bank in Netherlands saved EUR 2.5 million through Infosys–Broadcom Integrated Test Data Management Solution

Infosys helped a leading bank in Netherlands to meet their ever-growing demand for right test data across the hybrid SAP landscape by setting up an Enterprise-wide Test Data Management solution jointly with Broadcom. The centralized test data management solution helped the team to manage; all data related activities, enabled self-service for autonomous data provisioning and generation in a complex SAP landscape, Non-SAP apps and multiple databases. The solution improved test data quality, reduced data refresh effort by 60% and saved EUR 2.5 million every year.

For more information, contact askus@infosys.com

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